

<b>Notice of References Cited</b>	Application/Control No. 10/613,596		Applicant(s)/Patent Under Reexamination MCCARTY ET AL.	
	Examiner Dominic E. Rego		Art Unit 2684	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,754,354	06-2004	Lokhoff, Gerardus C. P.	381/77
*	B	US-2003/0095096	05-2003	Robbin et al.	345/156
*	C	US-2002/0135513	09-2002	Paschen et al.	342/371
*	D	US-5,428,341	06-1995	Takahashi, Keichi	340/506
*	E	US-2004/0097851	05-2004	Inada et al.	601/047
*	F	US-2004/0131193	07-2004	Kitamura, Mamoru	381/028
*	G	US-2004/0062270	04-2004	Son et al.	370/465
*	H	US-6,445,369	09-2002	Yang et al.	345/82
*	I	US-2002/0145509	10-2002	Karny et al.	340/310.06
*	J	US-5,491,755	02-1996	Vogt et al.	381/86
*	K	US-5,661,848	08-1997	Bonke et al.	711/112
*	L	US-2004/0250273	12-2004	Swix et al.	725/025
*	M	US-2002/0101357	08-2002	Gharapetian, Ara H.	340/825.69

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.